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## COMBINING ELECTRON MICROSCOPY WITH ATOMIC MODELS

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<b></b>		
	Part. T:	
	Sticking in the model	















Approache	s to docking
Compare atomic p density	ositions directly with
Convert atomic mo compare	odel to density, then
Convert atomic mo comething else, th	odel and density to ven compare

## Part II: Evaluating the quality of the fit

Similarit	y Measures
leasure the fit betw econstruction	veen atomic model and
laximum Likelihood nbiased estimate (N	gives the best possible Neyman and Pearson)
lany of the more co leasures are some a laximum likelihood	mmon similarity pproximation to









































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